(AUB a)	PATENT APPLICATION			
(Am) (S)	Sheet 1 of 2			
ATTY. DOCKET NO	SERIAL NO.			
FORM PTO-1449 70-10010958-1	10/047,344			
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT				
APPLICANT'S INFORMATION DISCLOSURE STATEMENT Kang Wu et al	Kang Wu et al			
FILING DATE	GROUP			
(Use several sheets if necessary) 01/15/2002	2184			

REFERENCE DESIGNATION

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FOREIGN PATENT DOCUMENTS

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20	EP 1132749 A	Sep 12, 2001	Toshinori Hosokawa et al	×		

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SA	Coudert, Olivier, "On Solving Covering Problems", 33rd Design Automation Conference, Proceedings 1996 (IEEE Cat.No.96CH35932), Proceedings of 33rd Design Automation Conference, Las Vegas, NV, USA, 3-7 June 1996, 1996, New York, NY, USA, ACM, USA, Pages(s) 197-202. XP002246-016 ISBN: 0-89791-779-0
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3 A	Coudert, Olivier, "Solving Graph Optimization Problems with ZBDDs", European Design and Test Conference, 1997, ED&TC 97, Proceedings Paris, France 17-20 March 1997, Los Alamitos, CA, USA, IEEE Comput. Soc, US, Page(s) 224-228. XP010218503 ISBN: 0-8186-7786-4

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